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| Search Notes  | Application/Control No. 10576819 | Applicant(s)/Patent Under Reexamination FUKUCHI ET AL. |
| | Examiner Wai-Sing Louie | Art Unit 2814 |

| SEARCHED | | | |
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| Class | Subclass | Date | Examiner |
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| SEARCH NOTES | | |
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| Search Notes | Date | Examiner |
| TFT, LCD, gate insulation, semiconductor active layer, source/ drain wiring, mobility, hydrogen content | 1/13/09 | WSL |

| INTERFERENCE SEARCH | | | |
|---------------------|----------|------|----------|
| Class | Subclass | Date | Examiner |
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